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## Information Disclosure Statement by Applicant

Applicant: Arman Sagatelian et al.

(Use several sheets if necessary)

Filed: January 22, 2002 Group: 2858

## U.S. Patent Documents

Init.		Document No.	Date	Name	Class	Subclass	Filing Date
1b	1	5,475,695	12/12/1995	Caywood et al.	371	27	03/19/1993

## Foreign Documents

								Translation	
Init.		Document No.	Date	Country	Class	Subclass	Yes	No	

## Other Documents (Including Author, Title, Date, Pertinent Pages, etc.)

cb	2	K. Tobin, "Automated Analysis for Rapid Defect Sourcing and Yield Learning", <u>Future Fab International</u> , 15 pages, Vol. 4, 1997 (no month).
cb	3	"Semiconductor Spatial Signature Analysis (SSA)", [Internet] <a href="http://www-ismv.icornl.gov/projects/SSA.html">http://www-ismv.icornl.gov/projects/SSA.html</a> , 6 pages, Revised March 31, 1999, printed 2/27/03
cb	4	J. Segal et al., "The Value of Electrical Bitmap Results from Embedded Memory Arrays for Rapid Yield Learning", Digest of Papers, 2 <sup>nd</sup> IEEE Latin American Test Workshop LATW2001, pp. 266-272, Feb. 2001.

Examiner

Cbwt

Date Considered

8-20-04

Examiner: Initial if citation considered, whether or not citation is in conference with MPEP 609; Draw line through citation if not conformance and not considered. Include a copy of this form with the next communication to applicant.